

General Description

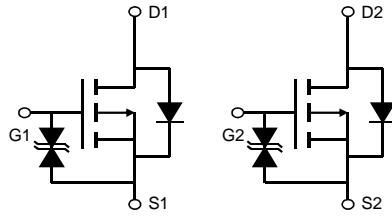
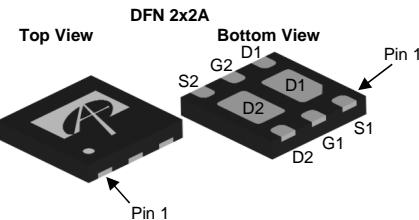
The AON2809 combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications.

Product Summary

V_{DS}	-12V
I_D (at $V_{GS}=-4.5V$)	-2A
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	< 68mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$)	< 90mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.8V$)	< 118mΩ

Typical ESD protection

HBM Class 2



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-12	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ^G	I_D	-2	A
		-1.6	
Pulsed Drain Current ^C	I_{DM}	-8	
Power Dissipation ^B	P_D	2.1	W
		1.3	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	50	60	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		80	100	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-12			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-12\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm6\text{V}$			±10	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.3	-0.6	-0.9	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-8			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$ $T_J=125^\circ\text{C}$		55 72	68 89	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-1\text{A}$		70	90	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-1\text{A}$		90	118	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-2\text{A}$		8		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_s	Maximum Body-Diode Continuous Current				-1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-6\text{V}, f=1\text{MHz}$		415		pF
C_{oss}	Output Capacitance			115		pF
C_{rss}	Reverse Transfer Capacitance			78		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		26		Ω
SWITCHING PARAMETERS						
$Q_g(4.5)$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, I_D=-2\text{A}$		4.4		nC
Q_{gs}	Gate Source Charge			0.8		nC
Q_{gd}	Gate Drain Charge			0.9		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-4.5\text{V}, V_{DS}=-6\text{V}, R_L=3\Omega, R_{\text{GEN}}=3\Omega$		11.8		ns
t_r	Turn-On Rise Time			24.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			54.5		ns
t_f	Turn-Off Fall Time			37.3		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-2\text{A}, dI/dt=100\text{A}/\mu\text{s}$		21		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-2\text{A}, dI/dt=100\text{A}/\mu\text{s}$		5		nC

A. The value of R_{QJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $R_{\text{QJA}} t \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C .

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

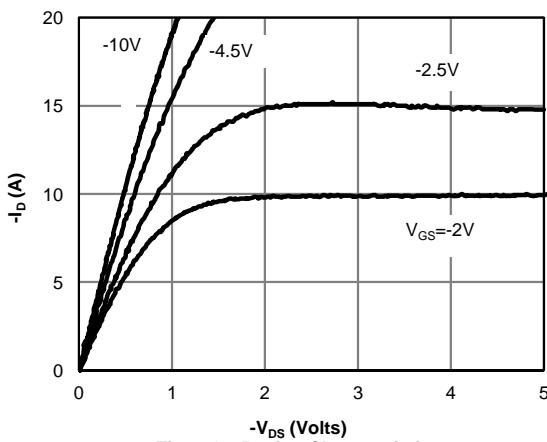
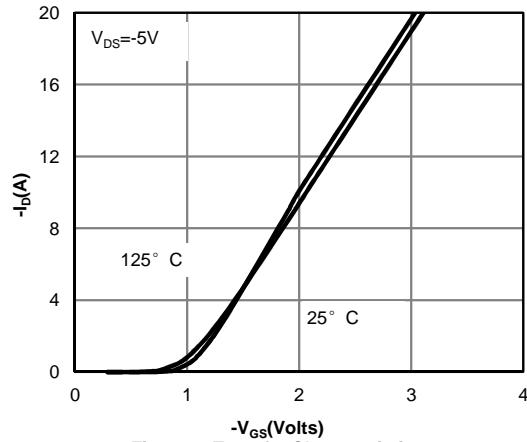
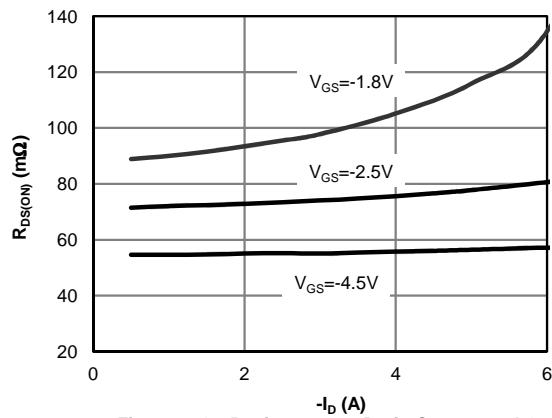
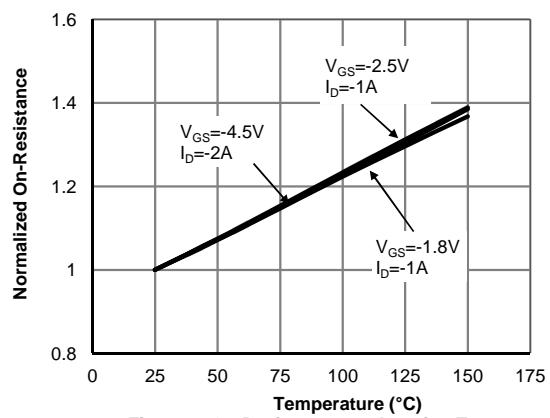
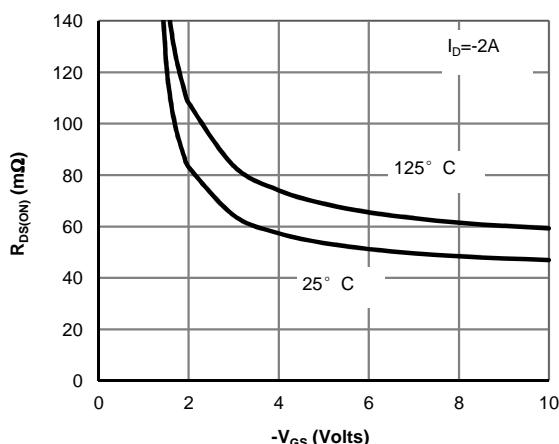
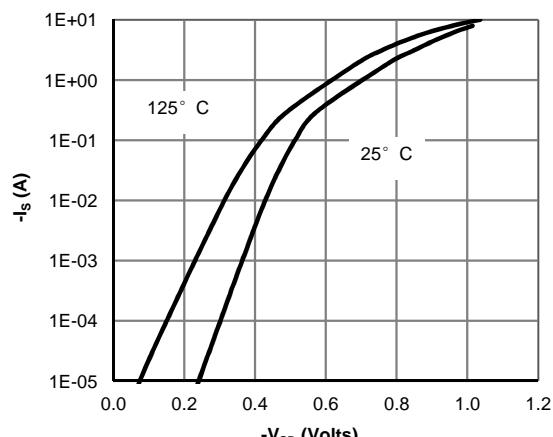
D. The R_{QJA} is the sum of the thermal impedance from junction to lead R_{QJL} and lead to ambient.

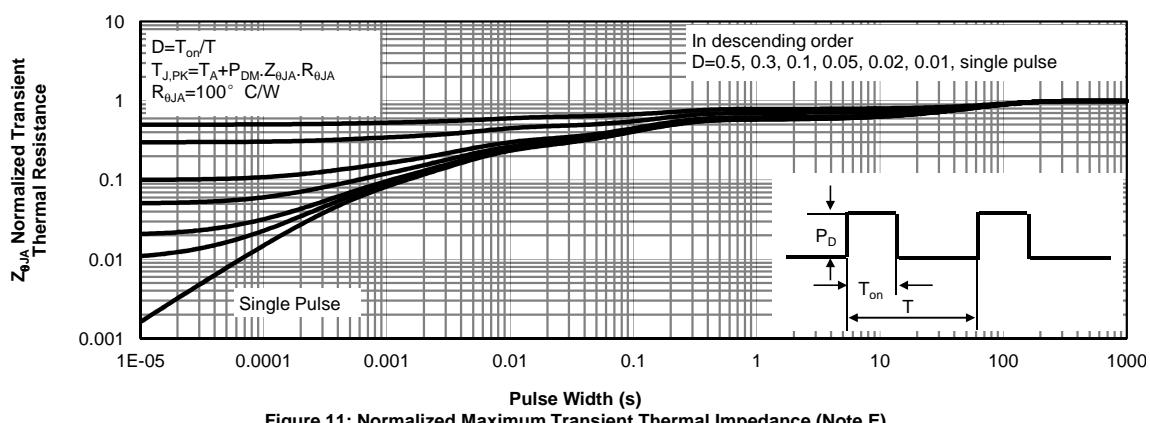
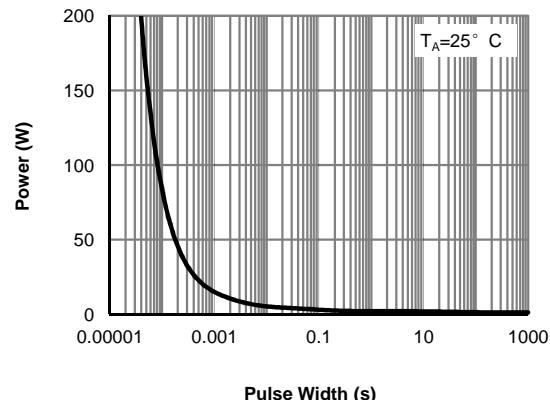
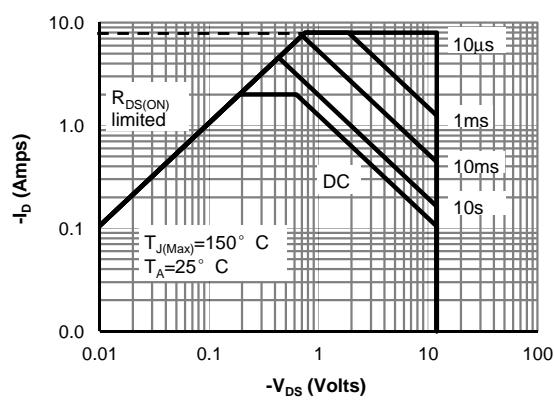
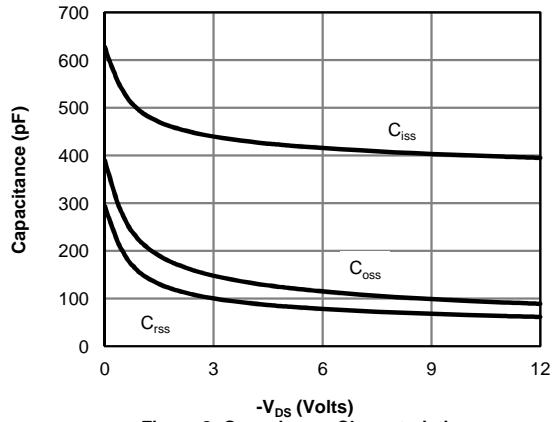
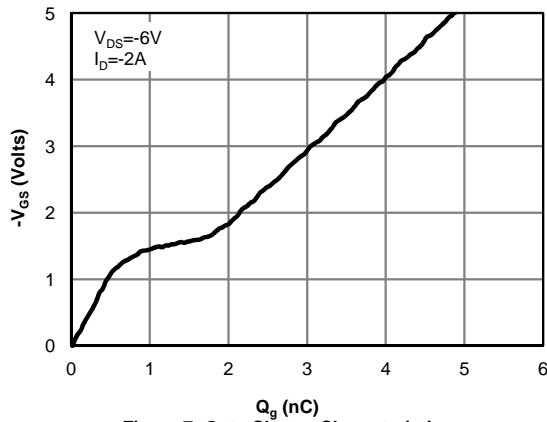
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

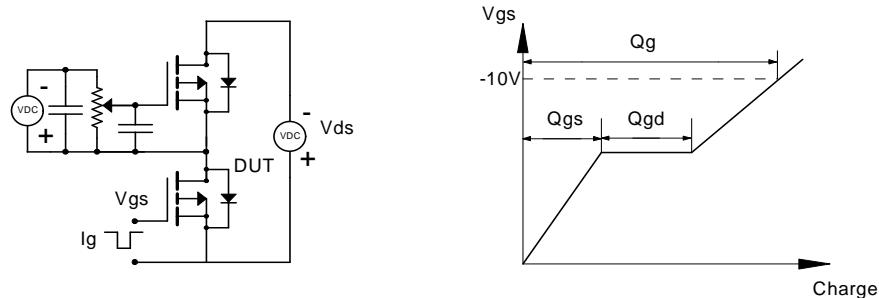
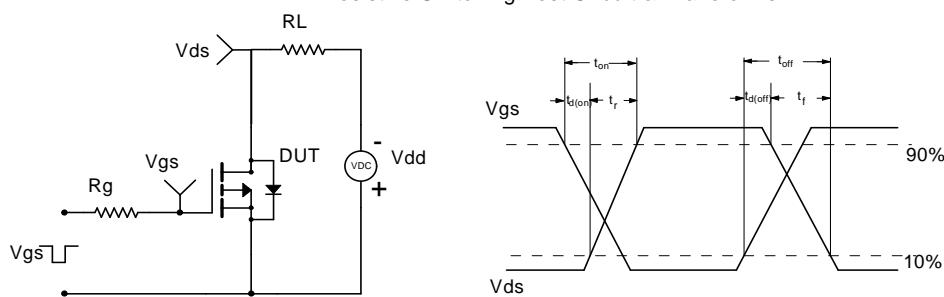
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics

Figure 2: Transfer Characteristics

Figure 3: On-Resistance vs. Drain Current and Gate Voltage

Figure 4: On-Resistance vs. Junction Temperature

Figure 5: On-Resistance vs. Gate-Source Voltage

Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
